

**2M × 8-Bit Dynamic RAM
2k Refresh
(Hyper Page Mode-EDO)**

**HYB 5117805/BSJ-50/-60
HYB 3117805/BSJ-50/-60**

Advanced Information

- 2 097 152 words by 8-bit organization
- 0 to 70 °C operating temperature
- Hyper Page Mode-EDO-operation
- Performance:

		-50	-60	
t_{RAC}	\overline{RAS} access time	50	60	ns
t_{CAC}	\overline{CAS} access time	13	15	ns
t_{AA}	Access time from address	25	30	ns
t_{RC}	Read/Write cycle time	84	104	ns
t_{HPC}	Hyper page mode (EDO) cycle time	20	25	ns

- Power dissipation:

	HYB 5117805		HYB 3117805		
	-50	-60	-50	-60	
Power Supply	5 ± 10%		3.3 ± 0.3 V		
Active	440	385	288	252	mW
TTL Standby	11		7.2		mW
CMOS Standby	5.5		3.6		mW

- Read, write, read-modify-write, \overline{CAS} -before- \overline{RAS} refresh, \overline{RAS} -only refresh, hidden refresh and test mode
- All inputs, outputs and clocks fully TTL (5 V versions) and LV-TTL (3.3 V version)-compatible
- 2048 refresh cycles / 32 ms (2k-refresh)
- Plastic Package: P-SOJ-28-3 400 mil

The HYB 5(3)117805 are 16 MBit dynamic RAMs based on the die revisions "G" & "F" and organized as 2 097 152 words by 8-bits. The HYB 5(3)117805 utilizes a submicron CMOS silicon gate process technology, as well as advanced circuit techniques to provide wide operating margins, both internally and for the system user. Multiplexed address inputs permit the HYB 5(3)117805BJ to be packaged in a standard SOJ-28 plastic packages. Package with 400 mil width are available. These packages provide high system bit densities and are compatible with commonly used automatic testing and insertion equipment.

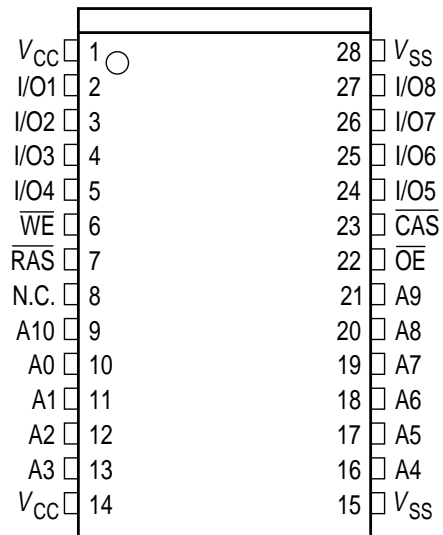
Ordering Information

Type	Ordering Code	Package	Descriptions
HYB 5117805BSJ-50	Q67100-Q1104	P-SOJ-28-3 400 mil	5 V 50 ns EDO-DRAM
HYB 5117805BSJ-60	Q67100-Q1105	P-SOJ-28-3 400 mil	5 V 60 ns EDO-DRAM
HYB 3117805BSJ-50	on request	P-SOJ-28-3 400 mil	3.3 V 50 ns EDO-DRAM
HYB 3117805BSJ-60	on request	P-SOJ-28-3 400 mil	3.3 V 60 ns EDO-DRAM

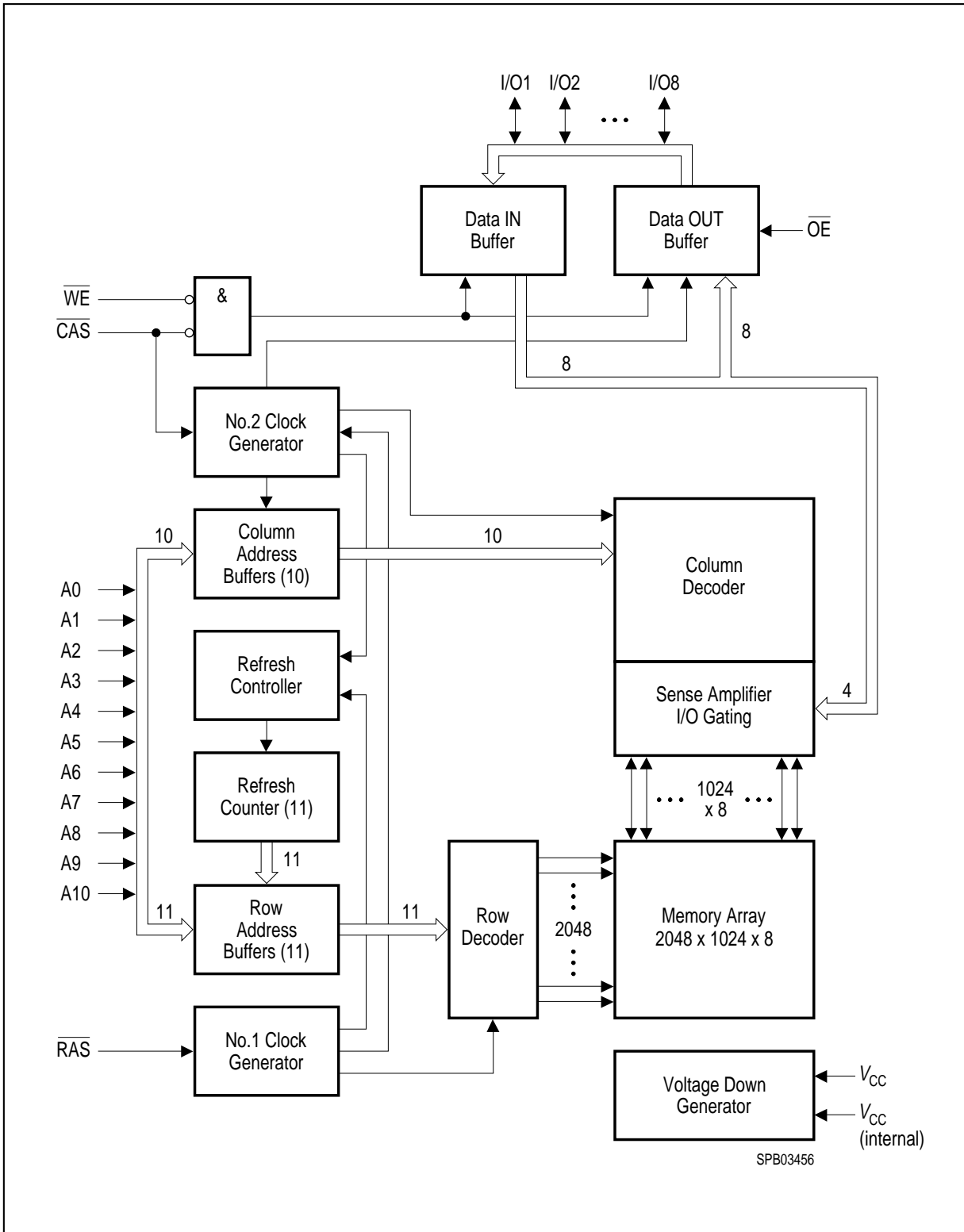
Pin Names and Configuration

A0 - A10	Row Address Inputs
A0 - A9	Column Address Inputs
$\overline{\text{RAS}}$	Row Address Strobe
$\overline{\text{OE}}$	Output Enable
I/O1 - I/O8	Data Input/Output
$\overline{\text{CAS}}$	Column Address Strobe
$\overline{\text{WE}}$	Read/Write Input
V_{CC}	Power Supply + 5 V for HYB 5117800 + 3.3 V for HYB 3117805
V_{SS}	Ground (0 V)
N.C.	Not Connected

P-SOJ-28 400 mil



SPP02803



Block Diagram

Absolute Maximum Ratings

Operating temperature range 0 to 70 °C
 Storage temperature range..... – 55 to 150 °C
 Input/output voltage (5 V versions) – 0.5 to min ($V_{CC} + 0.5$, 7.0) V
 Input/output voltage (3.3 V versions) – 0.5 to min ($V_{CC} + 0.5$, 4.6) V
 Power supply voltage (5 V versions) – 1.0 V to 7.0 V
 Power supply voltage (3.3 V versions) – 1.0 V to 4.6 V
 Power dissipation (5 V versions) 1.0 W
 Power dissipation (3.3 V versions) 0.5 W
 Data out current (short circuit) 50 mA

Note: Stresses above those listed under “Absolute Maximum Ratings” may cause permanent damage of the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

DC Characteristics

$T_A = 0$ to 70 °C, $V_{SS} = 0$ V, $t_T = 2$ ns

Parameter	Symbol	Limit Values		Unit	Test Condition
		min.	max.		

5 V Versions

Power supply voltage	V_{CC}	4.5	5.5	V	
Input high voltage	V_{IH}	2.4	$V_{CC} + 0.5$	V	¹
Input low voltage	V_{IL}	– 0.5	0.8	V	¹
Output high voltage ($I_{OUT} = - 5$ mA)	V_{OH}	2.4	–	V	¹
Output low voltage ($I_{OUT} = 4.2$ mA)	V_{OL}	–	0.4	V	¹

3.3 V Versions

Power supply voltage	V_{CC}	3.0	3.6	V	
Input high voltage	V_{IH}	2.0	$V_{CC} + 0.5$	V	¹
Input low voltage	V_{IL}	– 0.5	0.8	V	¹
TTL Output high voltage ($I_{OUT} = - 2$ mA)	V_{OH}	2.4	–	V	¹
TTL Output low voltage ($I_{OUT} = 2$ mA)	V_{OL}	–	0.4	V	¹
CMOS Output high voltage ($I_{OUT} = - 100$ μA)	V_{OH}	$V_{CC} - 0.2$	–	V	
CMOS Output low voltage ($I_{OUT} = 100$ μA)	V_{OL}	–	0.2	V	

Common Parameters

Input leakage current ($0 \text{ V} \leq V_{IH} \leq V_{CC} + 0.3 \text{ V}$, all other pins = 0 V)	$I_{I(L)}$	– 10	10	μA	¹
Output leakage current (DO is disabled, $0 \text{ V} \leq V_{OUT} \leq V_{CC} + 0.3 \text{ V}$)	$I_{O(L)}$	– 10	10	μA	¹

DC Characteristics (cont'd)

$T_A = 0$ to 70 °C, $V_{SS} = 0$ V, $t_T = 2$ ns

Parameter	Symbol	Limit Values		Unit	Test Condition
		min.	max.		
Average V_{CC} supply current -50 ns version -60 ns version (\overline{RAS} , \overline{CAS} , address cycling: $t_{RC} = t_{RC\ MIN.}$)	I_{CC1}	–	80 70	mA mA	2, 3, 4) 2, 3, 4
Standby V_{CC} supply current ($\overline{RAS} = \overline{CAS} = V_{IH}$)	I_{CC2}	–	2	mA	–
Average V_{CC} supply current, during \overline{RAS} -only refresh cycles -50 ns version -60 ns version (\overline{RAS} cycling, $\overline{CAS} = V_{IH}$, $t_{RC} = t_{RC\ MIN.}$)	I_{CC3}	–	80 70	mA mA	2, 4 2, 4
Average V_{CC} supply current, during hyper page mode (EDO) -50 ns version -60 ns version ($\overline{RAS} = V_{IL}$, \overline{CAS} , address cycling: $t_{PC} = t_{PC\ MIN.}$)	I_{CC4}	–	35 30	mA mA	2, 3, 4 2, 3, 4
Standby V_{CC} supply current ($\overline{RAS} = \overline{CAS} = V_{CC} - 0.2$ V)	I_{CC5}	–	1	mA	1
Average V_{CC} supply current, during \overline{CAS} -before- \overline{RAS} refresh mode -50 ns version -60 ns version (\overline{RAS} , \overline{CAS} cycling: $t_{RC} = t_{RC\ MIN.}$)	I_{CC6}	–	80 70	mA mA	2, 4 2, 4

Capacitance

$T_A = 0$ to 70 °C, $V_{CC} = 5$ V \pm 10 %, $f = 1$ MHz

Parameter	Symbol	Limit Values		Unit
		min.	max.	
Input capacitance (A0 to A10)	C_{I1}	–	5	pF
Input capacitance (\overline{RAS} , \overline{CAS} , \overline{WE} , \overline{OE})	C_{I2}	–	7	pF
I/O capacitance (I/O1 - I/O8)	C_{I0}	–	7	pF

AC Characteristics ^{5, 6}

$T_A = 0 \text{ to } 70 \text{ }^\circ\text{C}$, $V_{CC} = 5 \text{ V} \pm 10 \%$ / $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$, $t_T = 2 \text{ ns}$

Parameter	Symbol	Limit Values				Unit	Note
		-50		-60			
		min.	max.	min.	max.		

Common Parameters

Random read or write cycle time	t_{RC}	84	–	104	–	ns	
$\overline{\text{RAS}}$ precharge time	t_{RP}	30	–	40	–	ns	
$\overline{\text{RAS}}$ pulse width	t_{RAS}	50	10k	60	10k	ns	
$\overline{\text{CAS}}$ pulse width	t_{CAS}	8	10k	10	10k	ns	
Row address setup time	t_{ASR}	0	–	0	–	ns	
Row address hold time	t_{RAH}	8	–	10	–	ns	
Column address setup time	t_{ASC}	0	–	0	–	ns	
Column address hold time	t_{CAH}	8	–	10	–	ns	
$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ delay time	t_{RCD}	12	37	14	45	ns	
$\overline{\text{RAS}}$ to column address delay	t_{RAD}	10	25	12	30	ns	
$\overline{\text{RAS}}$ hold time	t_{RSH}	13	–	15	–	ns	
$\overline{\text{CAS}}$ hold time	t_{CSH}	40	–	50	–	ns	
$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ precharge time	t_{CRP}	5	–	5	–	ns	
Transition time (rise and fall)	t_T	1	50	1	50	ns	⁷
Refresh period	t_{REF}	–	32	–	32	ms	

Read Cycle

Access time from $\overline{\text{RAS}}$	t_{RAC}	–	50	–	60	ns	8, 9
Access time from $\overline{\text{CAS}}$	t_{CAC}	–	13	–	15	ns	8, 9
Access time from column address	t_{AA}	–	25	–	30	ns	8, 10
$\overline{\text{OE}}$ access time	t_{OEA}	–	13	–	15	ns	
Column address to $\overline{\text{RAS}}$ lead time	t_{RAL}	25	–	30	–	ns	
Read command setup time	t_{RCS}	0	–	0	–	ns	
Read command hold time	t_{RCH}	0	–	0	–	ns	¹¹
Read command hold time referenced to $\overline{\text{RAS}}$	t_{RRH}	0	–	0	–	ns	¹¹
$\overline{\text{CAS}}$ to output in low-Z	t_{CLZ}	0	–	0	–	ns	⁸
Output buffer turn-off delay	t_{OFF}	0	13	0	15	ns	¹²
Output turn-off delay from $\overline{\text{OE}}$	t_{OEZ}	0	13	0	15	ns	¹²

AC Characteristics (cont'd) ^{5, 6}

$T_A = 0$ to 70 °C, $V_{CC} = 5\text{ V} \pm 10\%$ / $V_{CC} = 3.3\text{ V} \pm 0.3\text{ V}$, $t_T = 2\text{ ns}$

Parameter	Symbol	Limit Values				Unit	Note
		-50		-60			
		min.	max.	min.	max.		
Data to $\overline{\text{CAS}}$ low delay	t_{DZC}	0	–	0	–	ns	13
Data to $\overline{\text{OE}}$ low delay	t_{DZO}	0	–	0	–	ns	13
$\overline{\text{CAS}}$ high to data delay	t_{CDD}	10	–	13	–	ns	14
$\overline{\text{OE}}$ high to data delay	t_{ODD}	10	–	13	–	ns	14

Write Cycle

Write command hold time	t_{WCH}	8	–	10	–	ns	
Write command pulse width	t_{WP}	8	–	10	–	ns	
Write command setup time	t_{WCS}	0	–	0	–	ns	15
Write command to $\overline{\text{RAS}}$ lead time	t_{RWL}	8	–	10	–	ns	
Write command to $\overline{\text{CAS}}$ lead time	t_{CWL}	8	–	10	–	ns	
Data setup time	t_{DS}	0	–	0	–	ns	16
Data hold time	t_{DH}	8	–	10	–	ns	16

Read-Modify-Write Cycle

Read-write cycle time	t_{RWC}	113	–	138	–	ns	
$\overline{\text{RAS}}$ to $\overline{\text{WE}}$ delay time	t_{RWD}	64	–	77	–	ns	15
$\overline{\text{CAS}}$ to $\overline{\text{WE}}$ delay time	t_{CWD}	27	–	32	–	ns	15
Column address to $\overline{\text{WE}}$ delay time	t_{AWD}	39	–	47	–	ns	15
$\overline{\text{OE}}$ command hold time	t_{OEH}	10	–	13	–	ns	

Hyper Page Mode (EDO) Cycle

Hyper page mode (EDO) cycle time	t_{HPC}	20	–	25	–	ns	
$\overline{\text{CAS}}$ precharge time	t_{CP}	8	–	10	–	ns	
Access time from $\overline{\text{CAS}}$ precharge	t_{CPA}	–	27	–	32	ns	7
Output data hold time	t_{COH}	5	–	5	–	ns	
$\overline{\text{RAS}}$ pulse width in EDO mode	t_{RAS}	50	200k	60	200k	ns	
$\overline{\text{CAS}}$ precharge to $\overline{\text{RAS}}$ delay	t_{RHCP}	27	–	32	–	ns	
$\overline{\text{OE}}$ setup time prior to $\overline{\text{CAS}}$	t_{OES}	5	–	5	–	5	

AC Characteristics (cont'd) ^{5, 6}

$T_A = 0$ to 70 °C, $V_{CC} = 5$ V ± 10 % / $V_{CC} = 3.3$ V ± 0.3 V, $t_f = 2$ ns

Parameter	Symbol	Limit Values				Unit	Note
		-50		-60			
		min.	max.	min.	max.		

Hyper Page Mode (EDO) Read-Modify-Write Cycle

Hyper page mode (EDO) read-write cycle time	t_{PRWC}	58	–	68	–	ns	
\overline{CAS} precharge to \overline{WE}	t_{CPWD}	41	–	49	–	ns	

\overline{CAS} -before- \overline{RAS} Refresh Cycle

\overline{CAS} setup time	t_{CSR}	10	–	10	–	ns	
\overline{CAS} hold time	t_{CHR}	10	–	10	–	ns	
\overline{RAS} to \overline{CAS} precharge time	t_{RPC}	5	–	5	–	ns	
Write to \overline{RAS} precharge time	t_{WRP}	10	–	10	–	ns	
Write hold time referenced to \overline{RAS}	t_{WRH}	10	–	10	–	ns	

\overline{CAS} -before- \overline{RAS} Counter Test Cycle

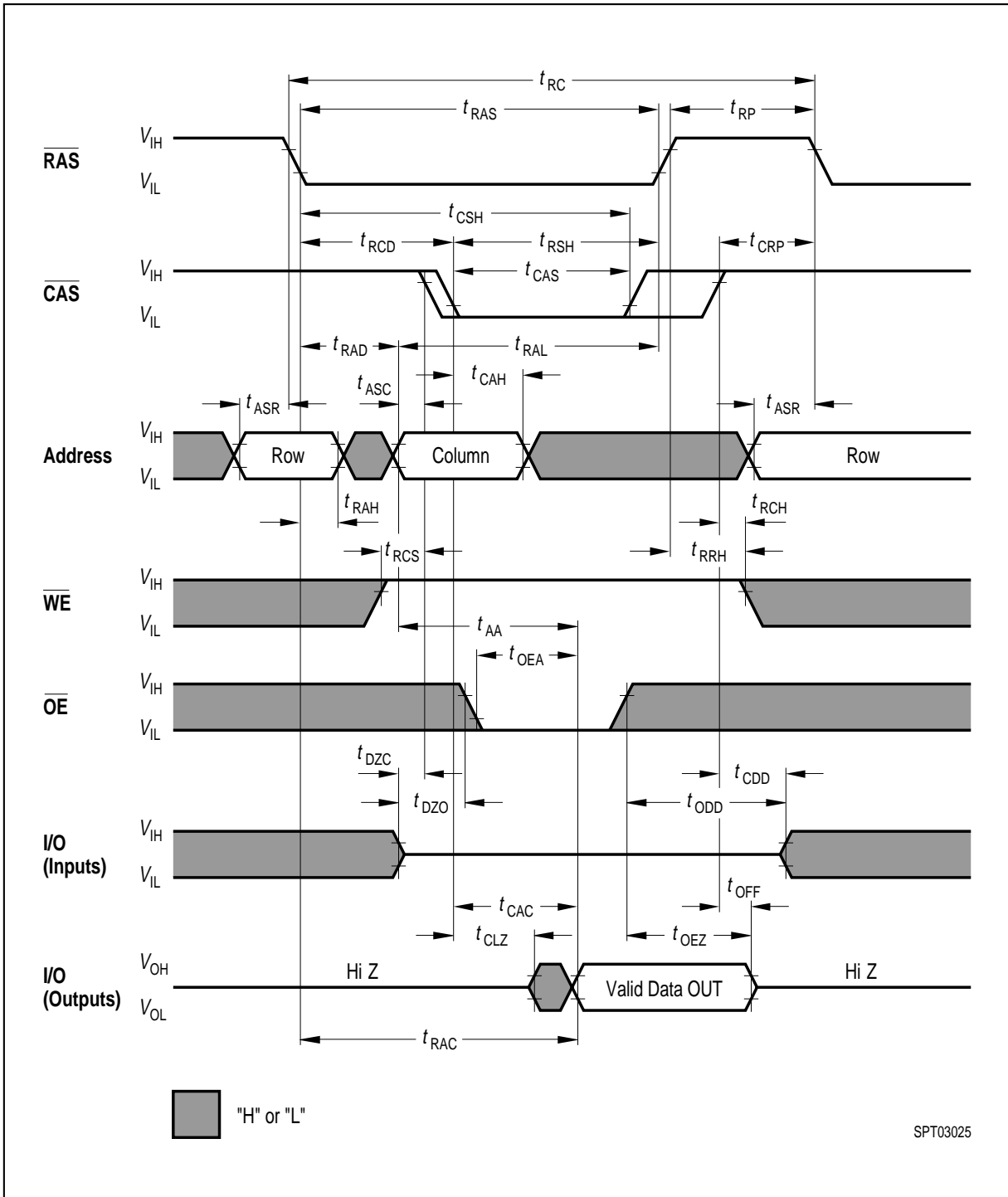
\overline{CAS} precharge time (\overline{CAS} -before- \overline{RAS} counter test cycle)	t_{CPT}	35	–	40	–	ns	
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Test Mode

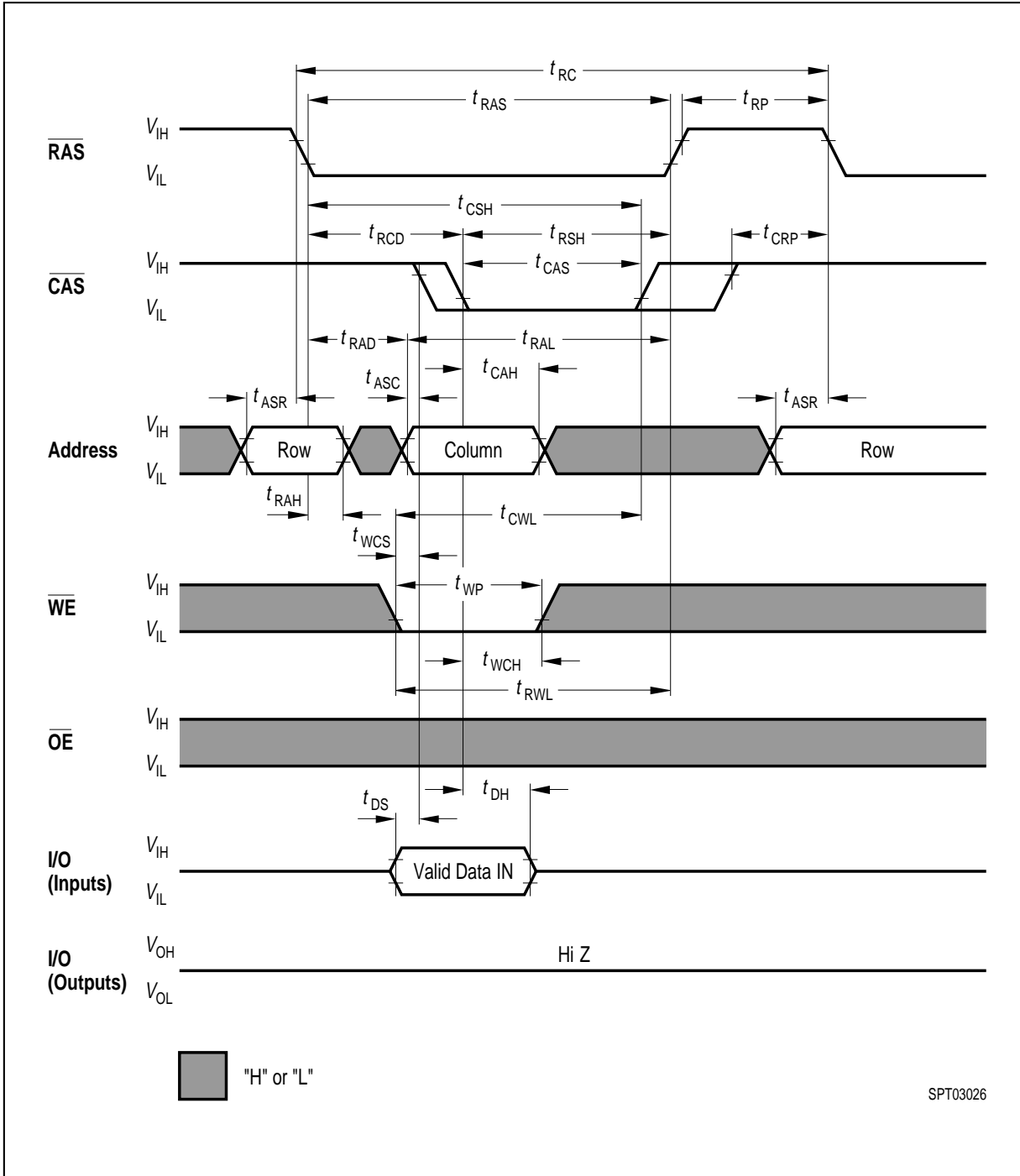
Write command setup time	t_{WTS}	10	–	10	–	ns	
Write command hold time	t_{WTH}	10	–	10	–	ns	
\overline{CAS} hold time	t_{CHRT}	30	–	30	–	ns	
\overline{RAS} hold time in test mode	t_{RAHT}	30	–	30	–	ns	

Notes

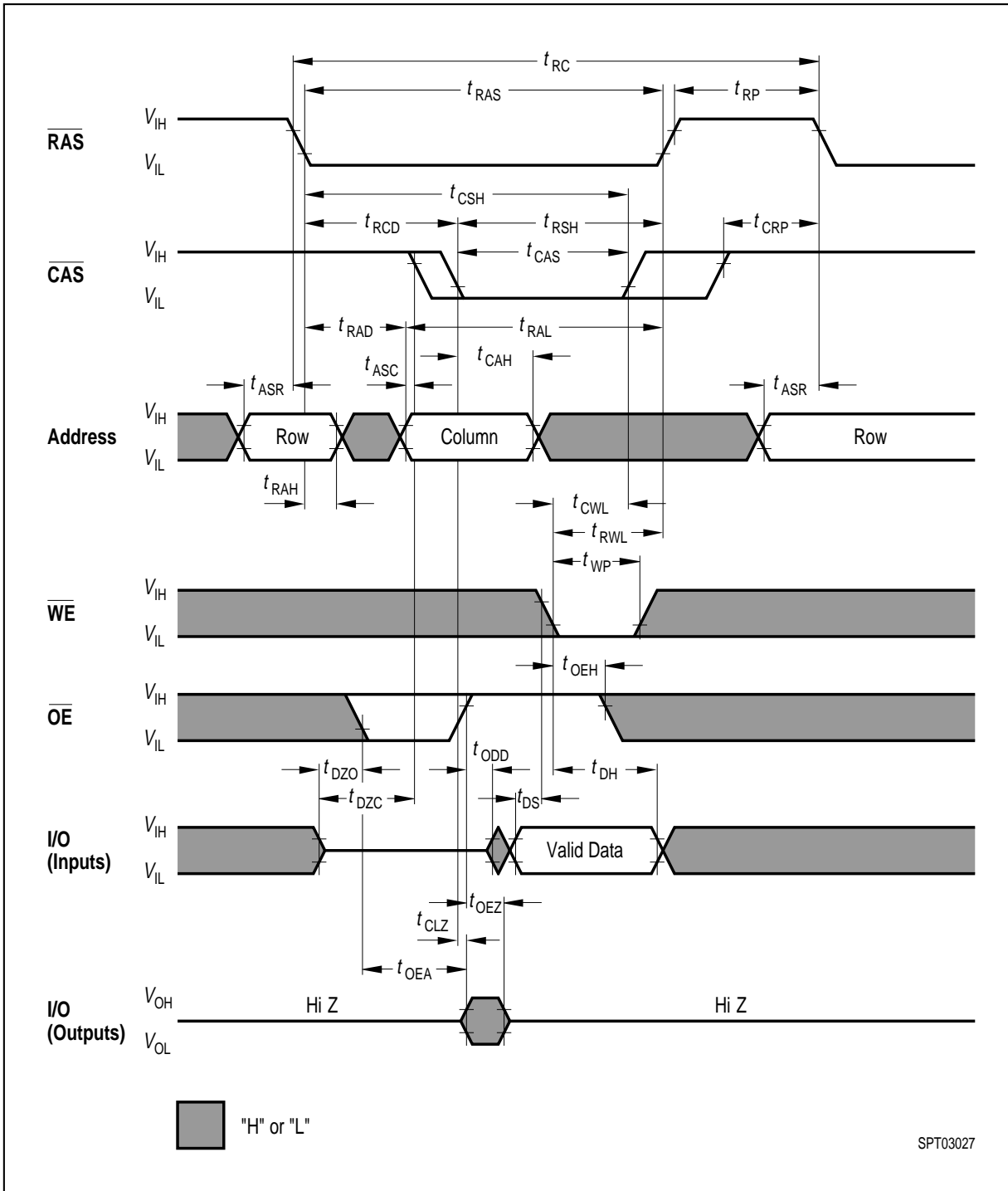
1. All voltages are referenced to V_{SS} .
2. I_{CC1} , I_{CC3} , I_{CC4} and I_{CC6} depend on cycle rate.
3. I_{CC1} and I_{CC4} depend on output loading. Specified values are obtained with the output open.
4. Address can be changed once or less while $\overline{RAS} = V_{IL}$. In case of I_{CC4} it can be changed once or less during a hyper page mode (EDO) cycle
5. An initial pause of 200 μs is required after power-up followed by 8 \overline{RAS} cycles of which at least one cycle has to be a refresh cycle, before proper device operation is achieved. In case of using the internal refresh counter, a minimum of 8 \overline{CAS} -before- \overline{RAS} initialization cycles instead of 8 \overline{RAS} cycles are required.
6. AC measurements assume $t_T = 2$ ns.
7. $V_{IH(MIN)}$ and $V_{IL(MAX)}$ are reference levels for measuring timing of input signals. Transition times are also measured between V_{IH} and V_{IL} .
8. Measured with the specified current load and 100 pF at $V_{OL} = 0.8$ V and $V_{OH} = 2.0$ V. Access time is determined by the latter of t_{RAC} , t_{CAC} , t_{AA} , t_{CPA} , t_{OEA} . t_{CAC} is measured from tristate.
9. Operation within the $t_{RCD(MAX)}$ limit ensures that $t_{RAC(MAX)}$ can be met. $t_{RCD(MAX)}$ is specified as a reference point only. If t_{RCD} is greater than the specified $t_{RCD(MAX)}$ limit, then access time is controlled by t_{CAC} .
10. Operation within the $t_{RAD(MAX)}$ limit ensures that $t_{RAC(MAX)}$ can be met. $t_{RAD(MAX)}$ is specified as a reference point only. If t_{RAD} is greater than the specified $t_{RAD(MAX)}$ limit, then access time is controlled by t_{AA} .
11. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
12. $t_{OFF(MAX)}$, $t_{OEZ(MAX)}$ define the time at which the output achieves the open-circuit conditions and are not referenced to output voltage levels. t_{OFF} is referenced from the rising edge of \overline{RAS} or \overline{CAS} , whichever occurs last.
13. Either t_{DZC} or t_{DZO} must be satisfied.
14. Either t_{CDD} or t_{ODD} must be satisfied.
15. t_{WCS} , t_{RWD} , t_{CWD} and t_{AWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} > t_{WCS(MIN)}$, the cycle is an early write cycle and data out pin will remain open-circuit (high impedance) through the entire cycle; if $t_{RWD} > t_{RWD(MIN)}$, $t_{CWD} > t_{CWD(MIN)}$ and $t_{AWD} > t_{AWD(MIN)}$, the cycle is a read-write cycle and I/O will contain data read from the selected cells. If neither of the above sets of conditions is satisfied, the condition of I/O (at access time) is indeterminate.
16. These parameters are referenced to the \overline{CAS} leading edge in early write cycles and to the \overline{WE} leading edge in read-write cycles.



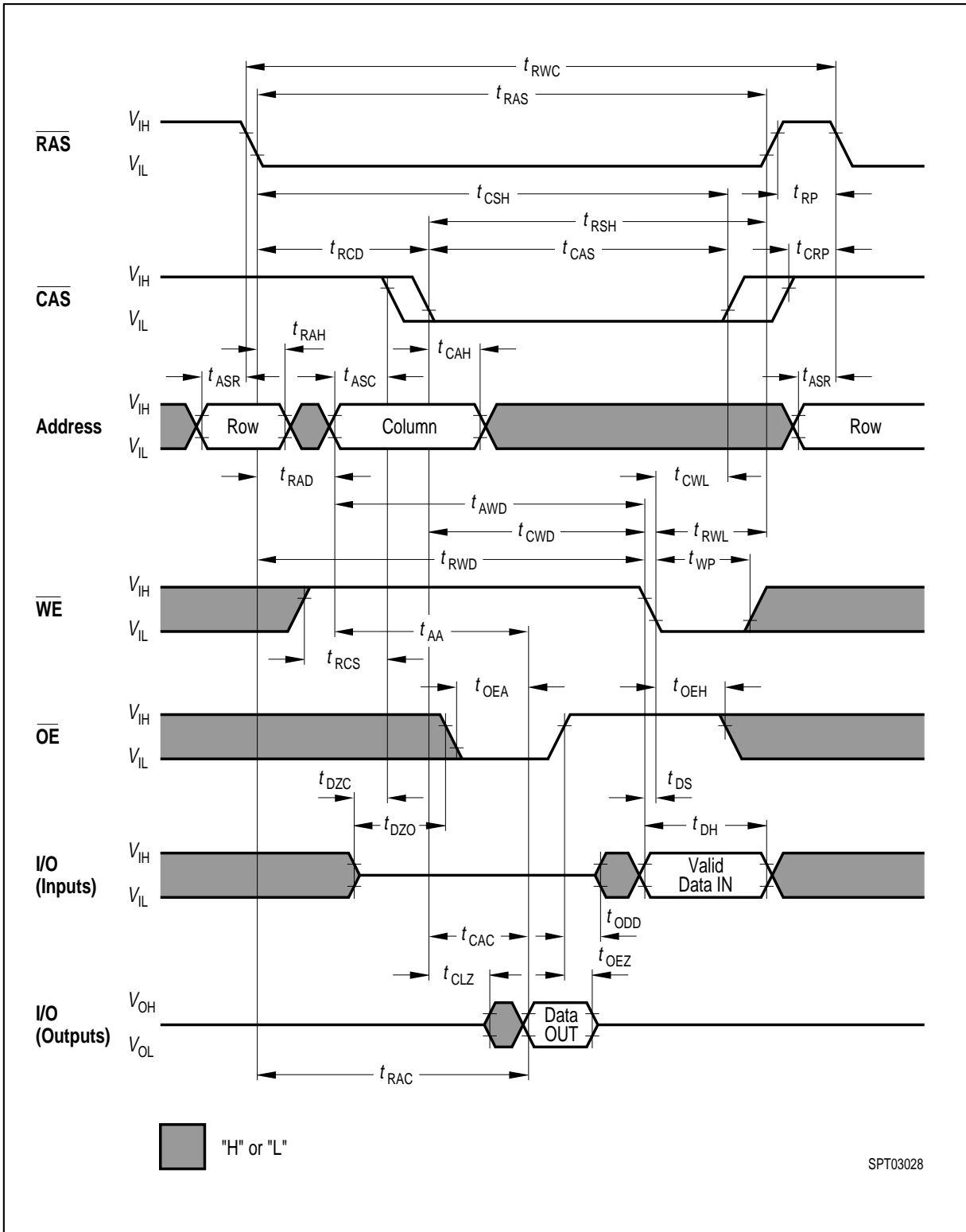
Read Cycle



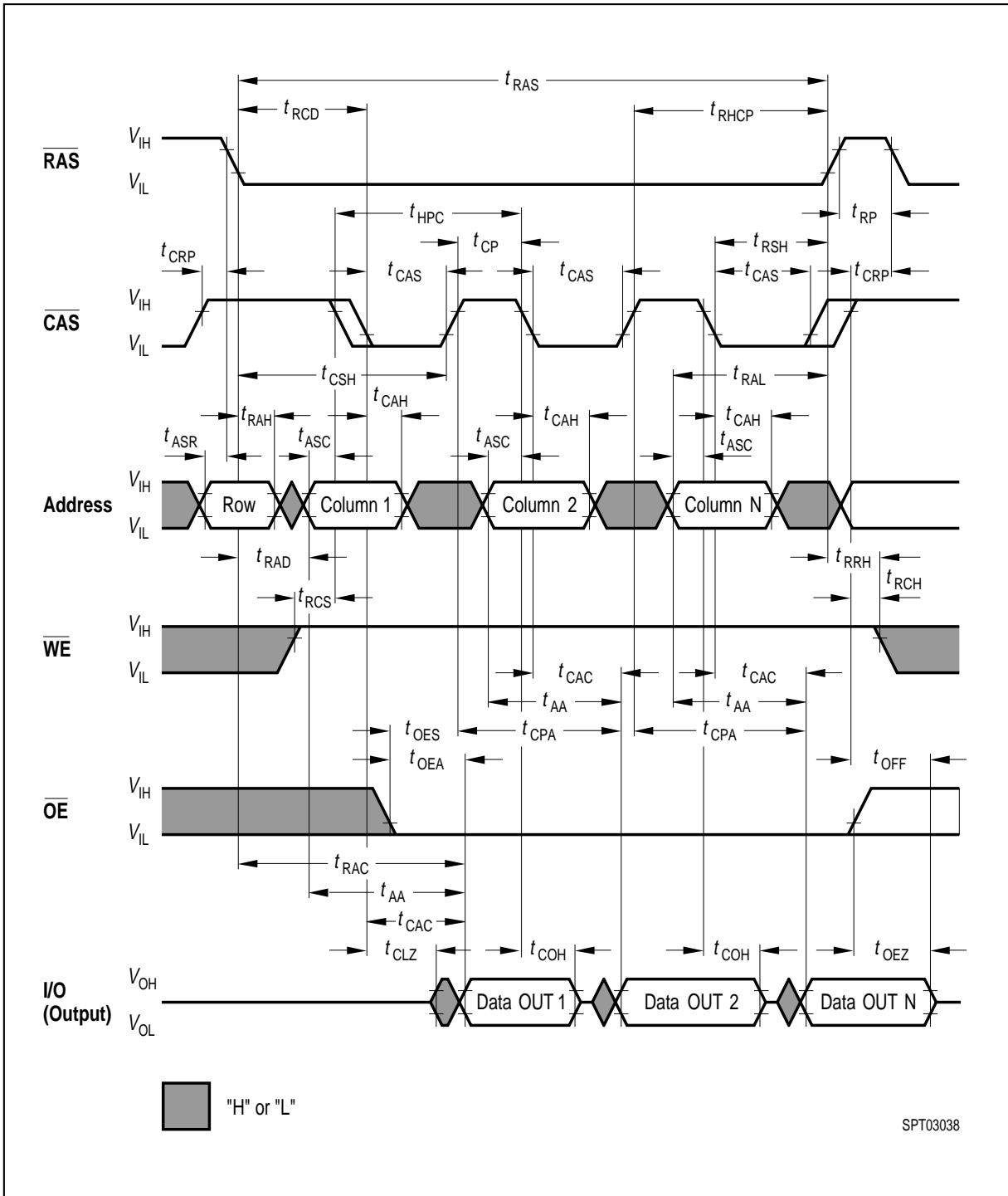
Write Cycle (Early Write)



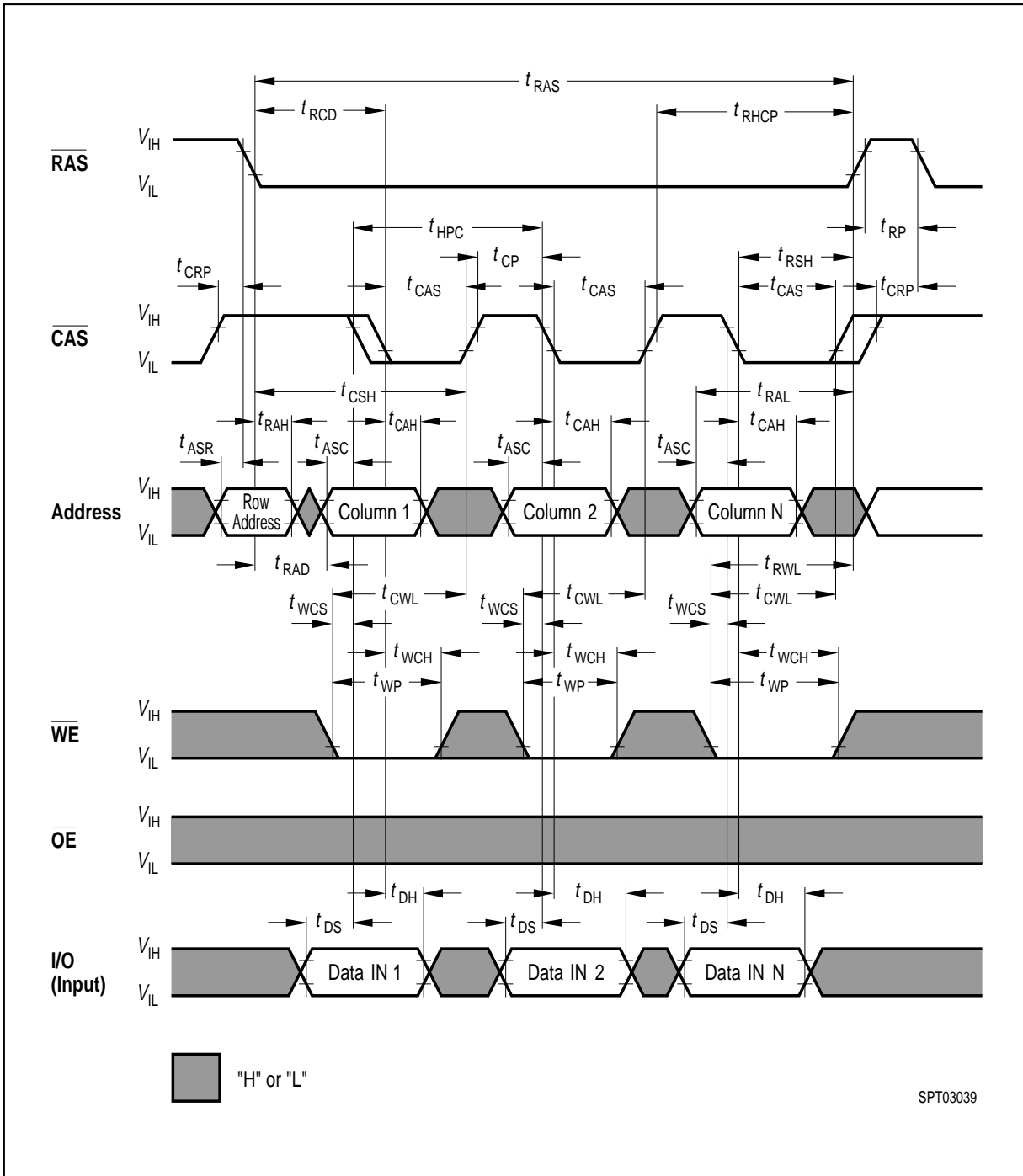
Write Cycle (\overline{OE} Controlled Write)



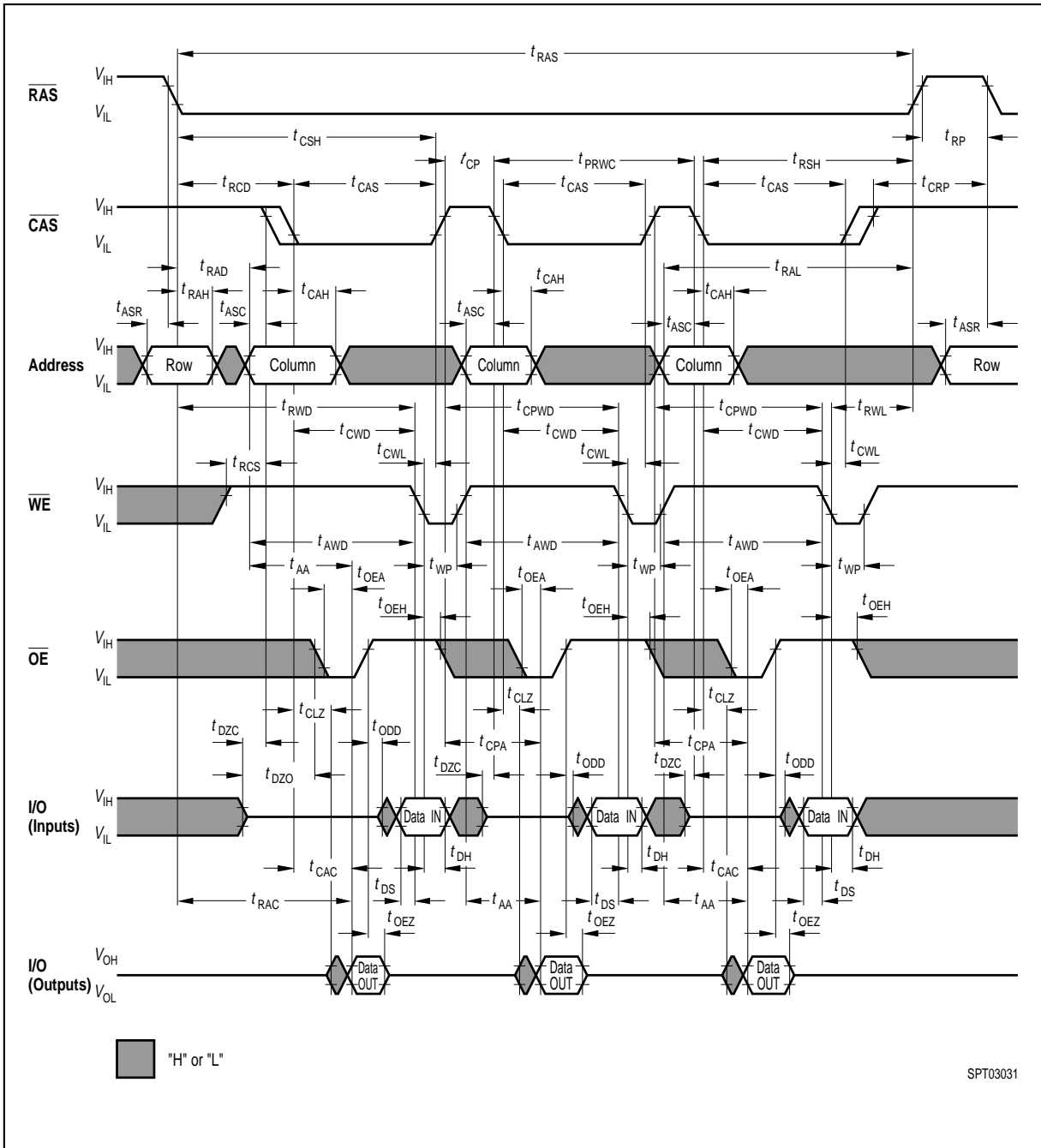
Read-Write (Read-Modify-Write) Cycle



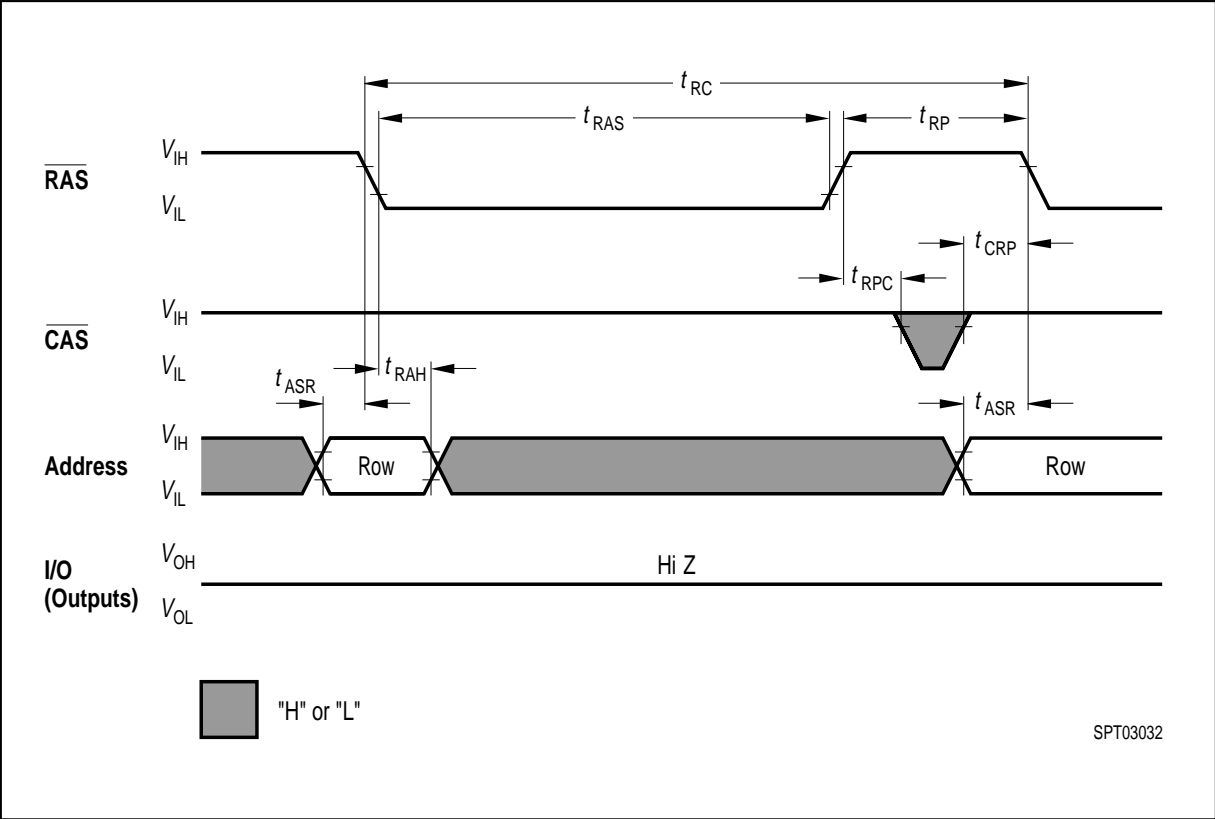
Hyper Page Mode (EDO) Read Cycle



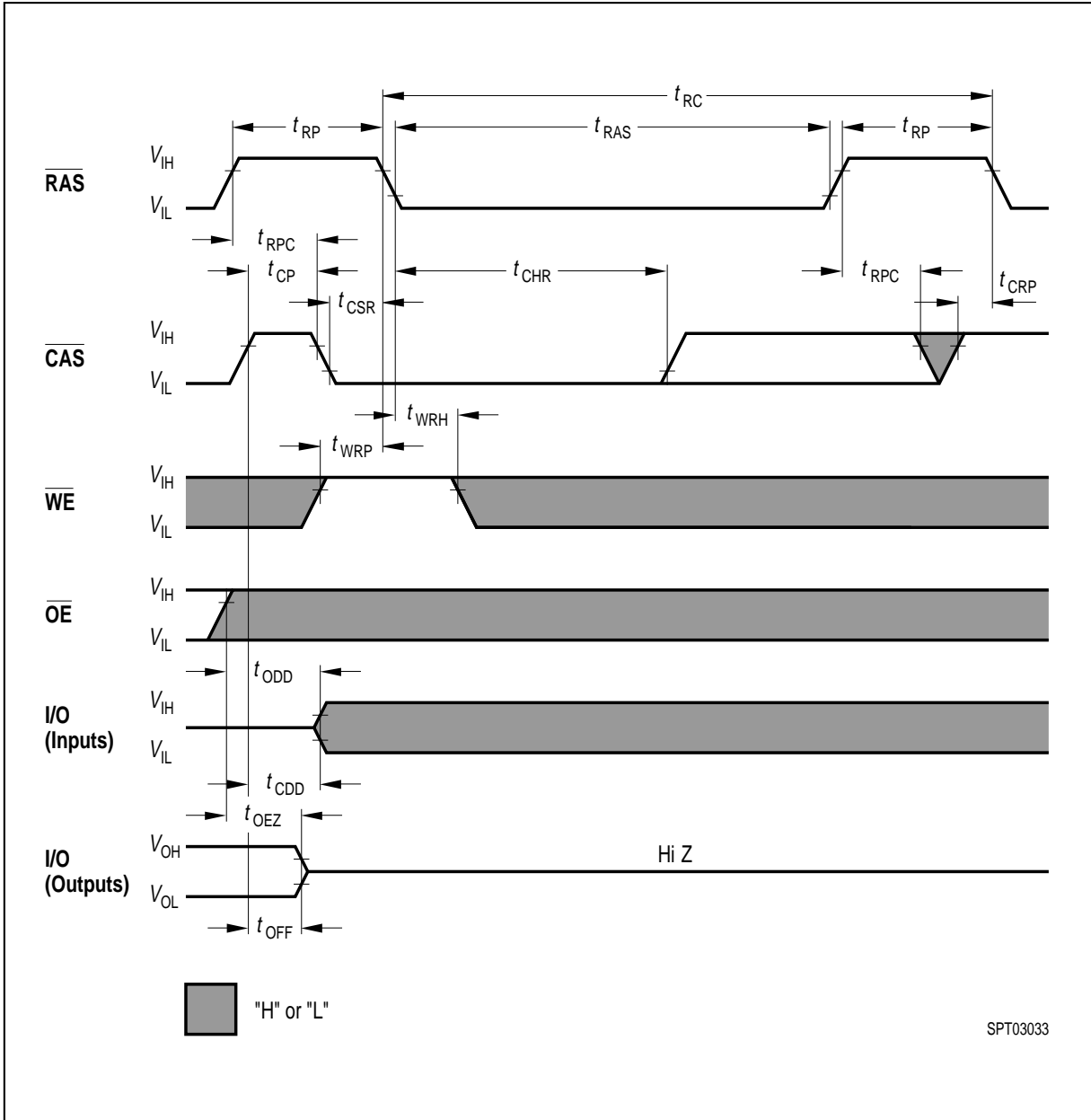
Hyper Page Mode (EDO) Early Write Cycle



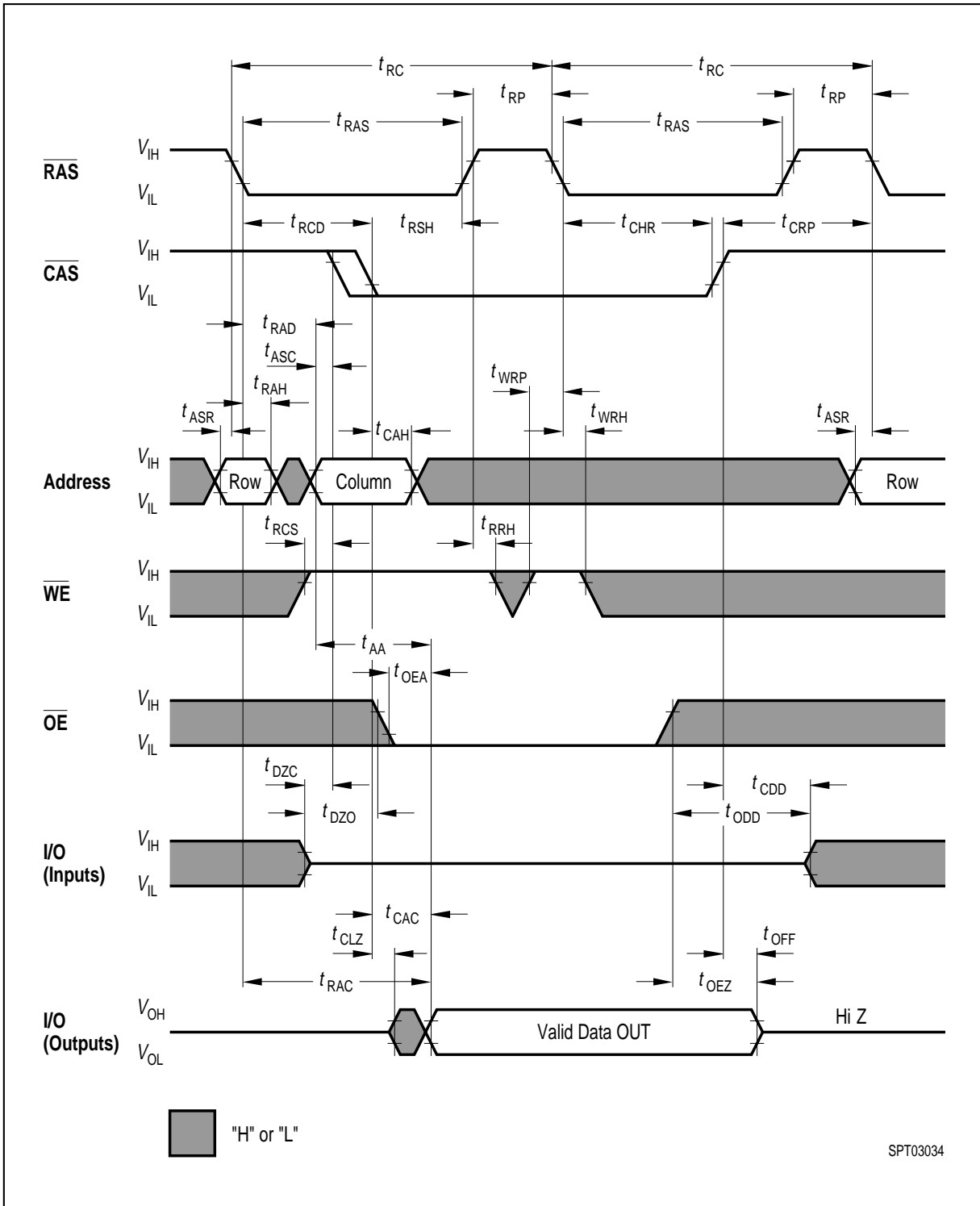
Hyper Page Mode (EDO) Late Write and Read-Modify-Write Cycle



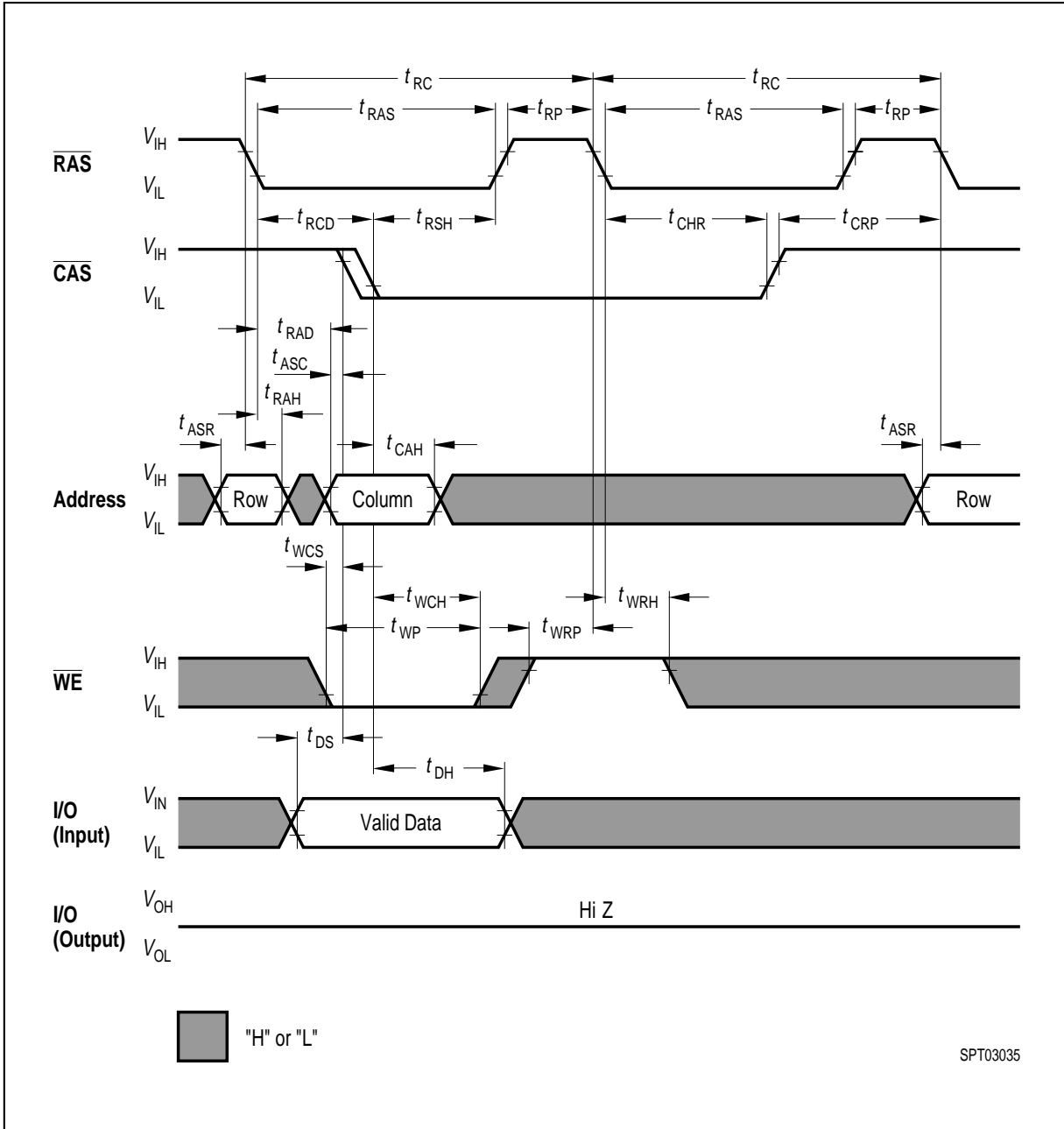
RAS-only Refresh Cycle



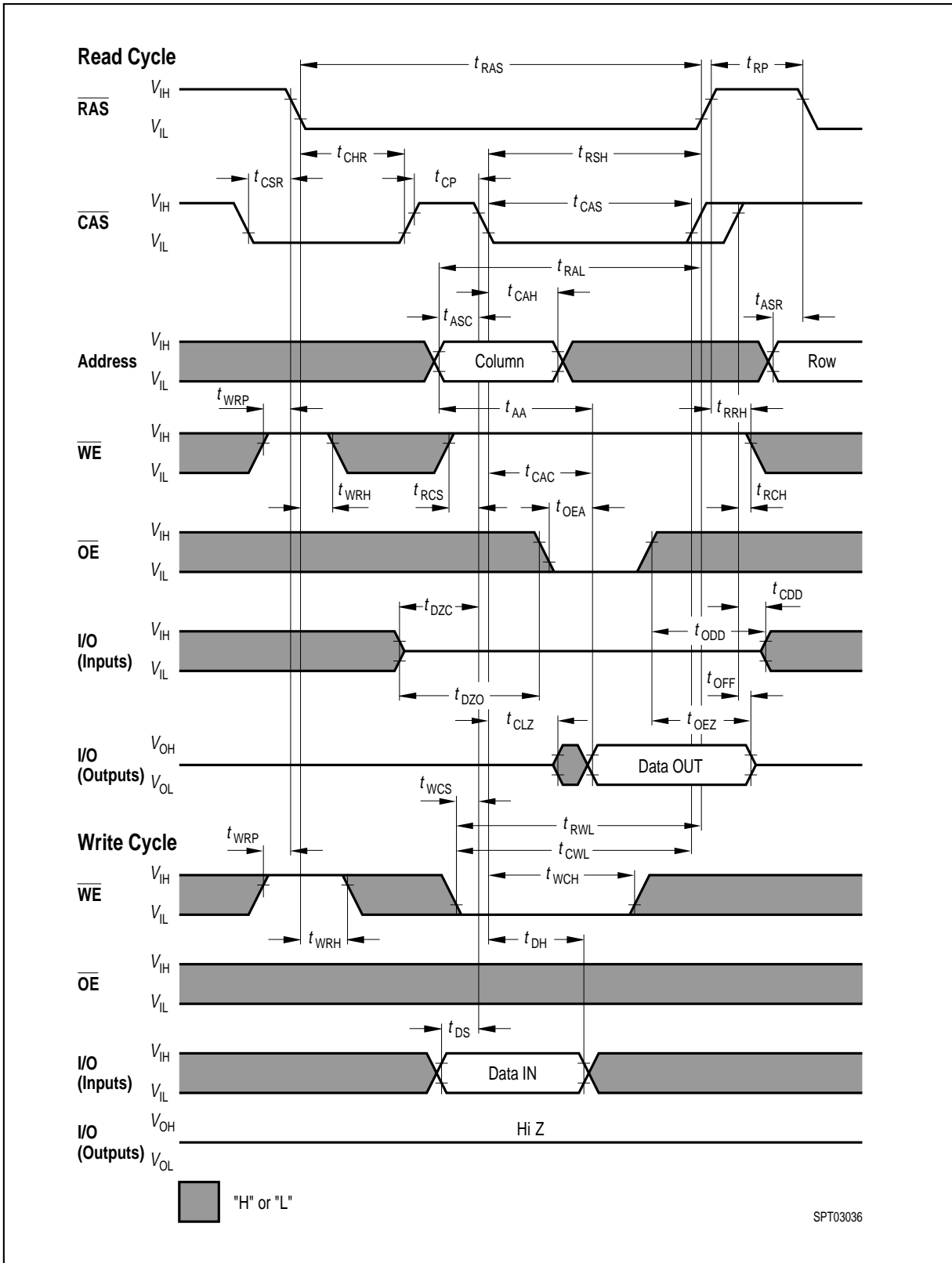
CAS-before-RAS Refresh Cycle



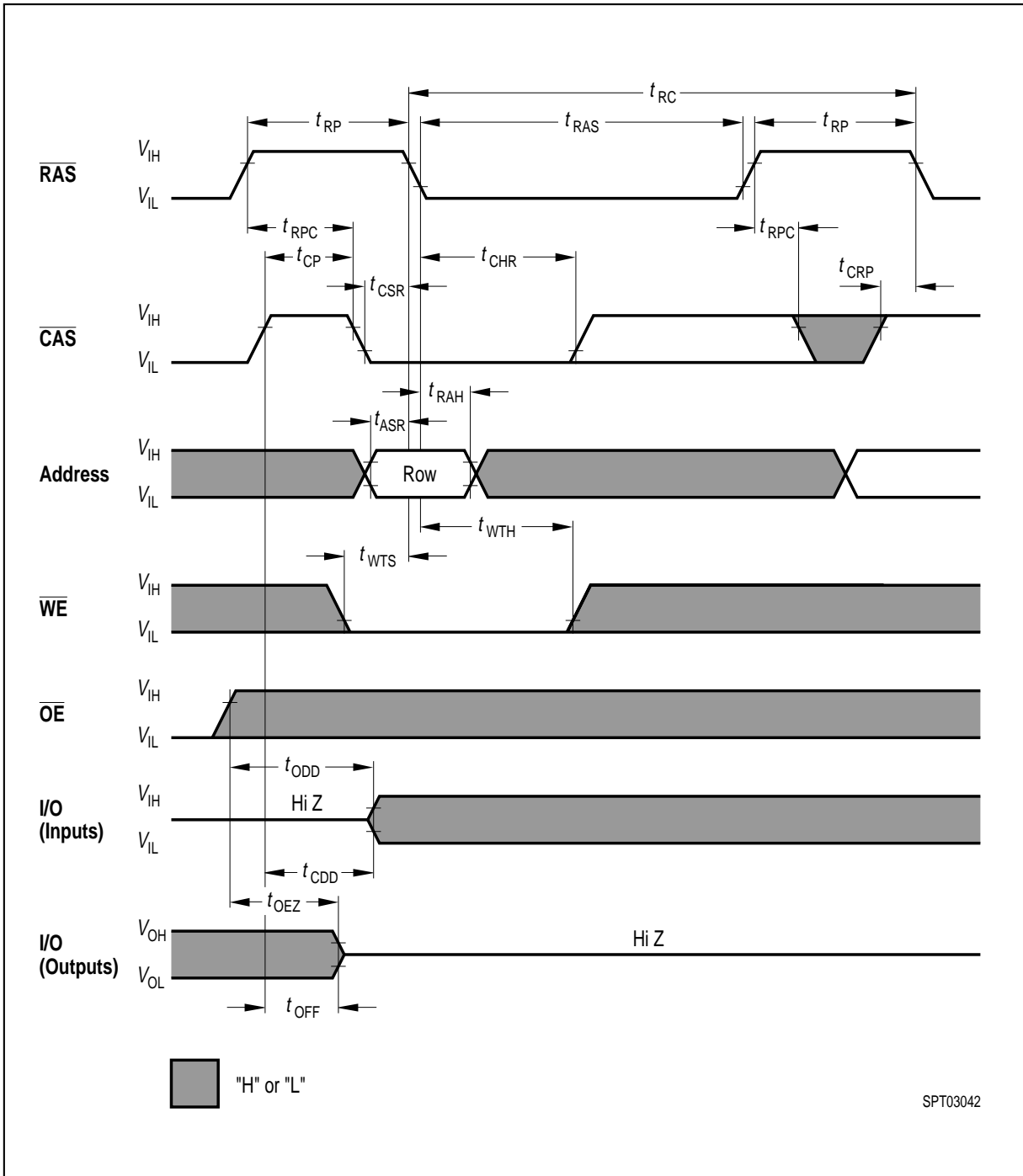
Hidden Refresh Cycle (Read) Cycle



Hidden Refresh Early Write Cycle

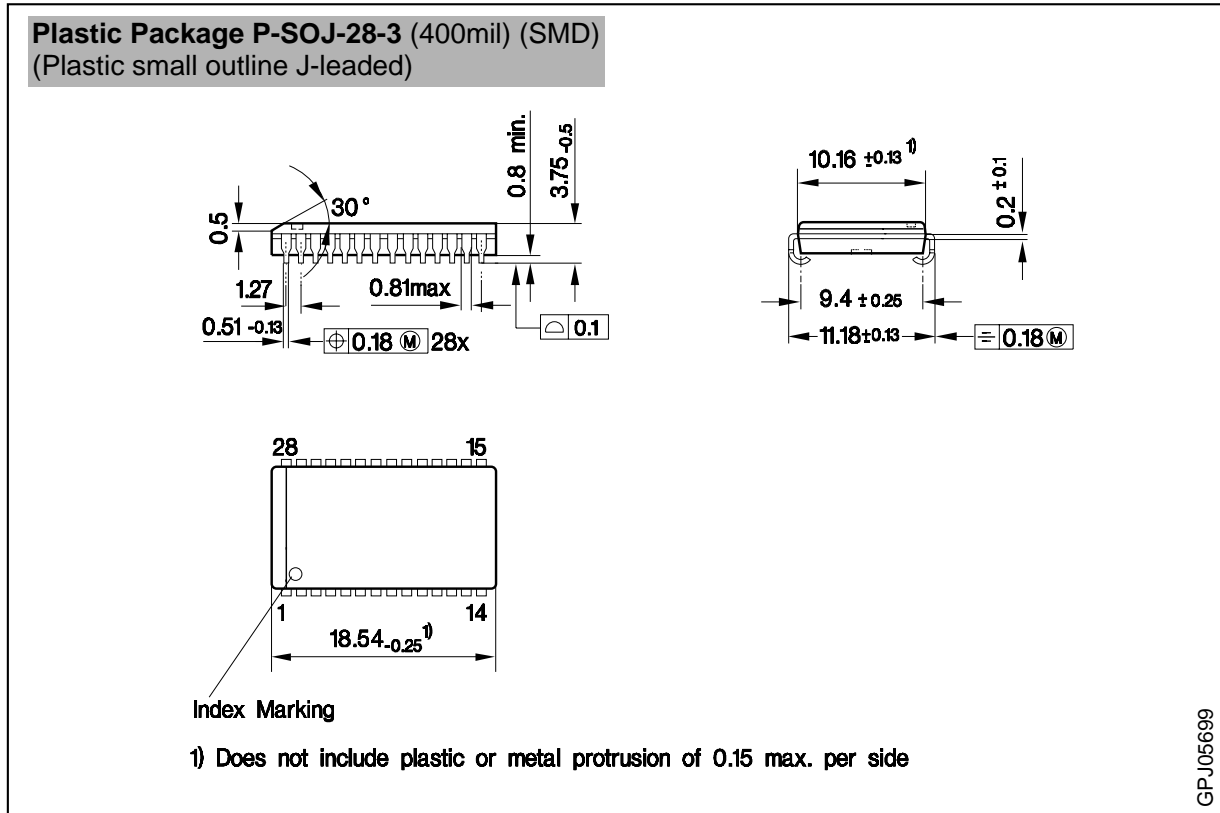


CAS-before-RAS Refresh Counter Test Cycle



Test Mode Entry

Package Outlines



Sorts of Packing

Package outlines for tubes, trays etc. are contained in our Data Book "Package Information".

SMD = Surface Mounted Device

Dimensions in mm